Special Issue

Application of Machine Learning in Computer-Aided Diagnosis

Message from the Guest Editor

Computer-assisted diagnosis (CAD) is a diagnostic method that uses a computer to analyze images to output a second opinion about the diagnosis, which is then used by the physician to make a diagnosis. With the emergence of various deep learning techniques, the processing capabilities of CAD have also undergone a significant improvement. Various applications have been developed for medical image classification, segmentation, and prediction. This Special Issue invites the submission of research which focuses on the application of machine learning using the CAD technique. Keywords

- machine learning
- computer-aided diagnosis
- deep learning
- medical imaging
- image analysis
- image classification
- image segmentation

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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